

# High Spatial and Temporal Resolution Detectors for 3D studies using 30-100 keV X-rays.

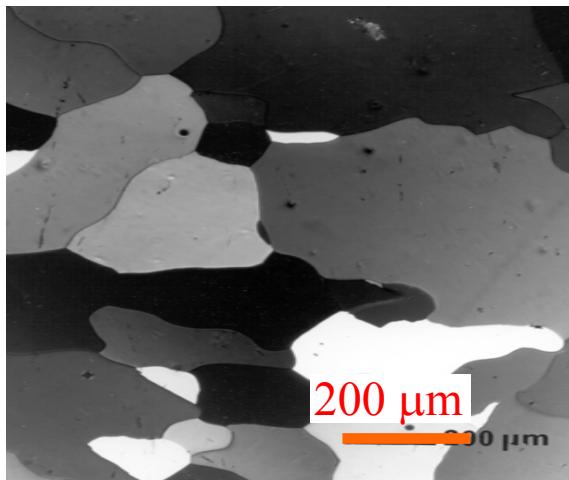
Henning Friis Poulsen

*Center for Fundamental Research: Metal structures in 4D  
Risø National Laboratory, Denmark*

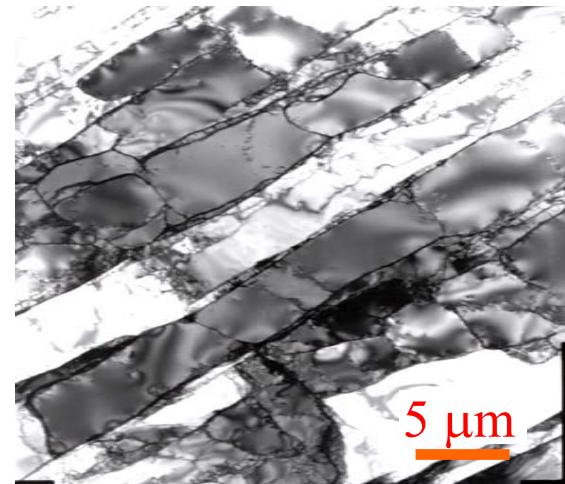


# Metal Structures

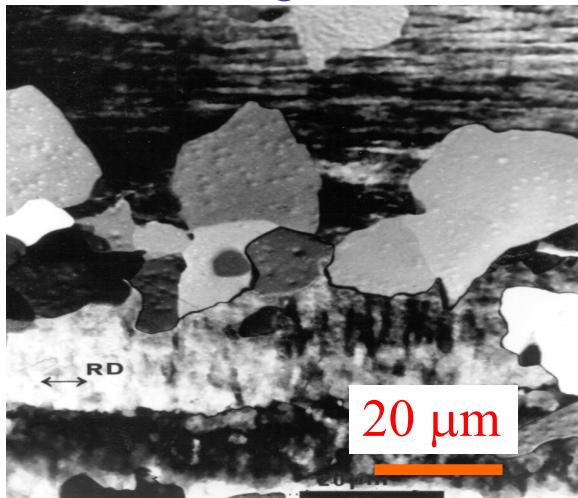
1. Undeformed :



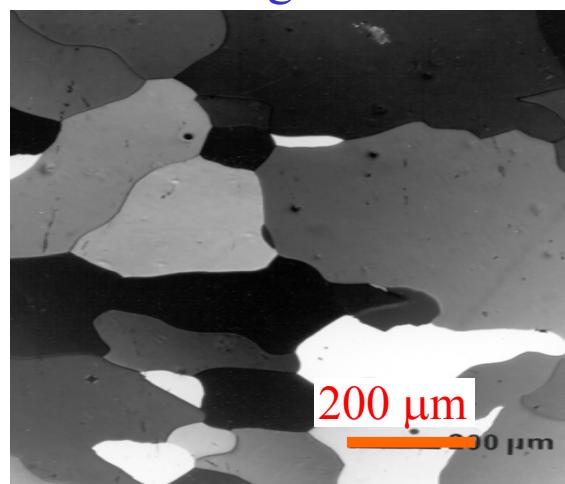
2. Deformation:



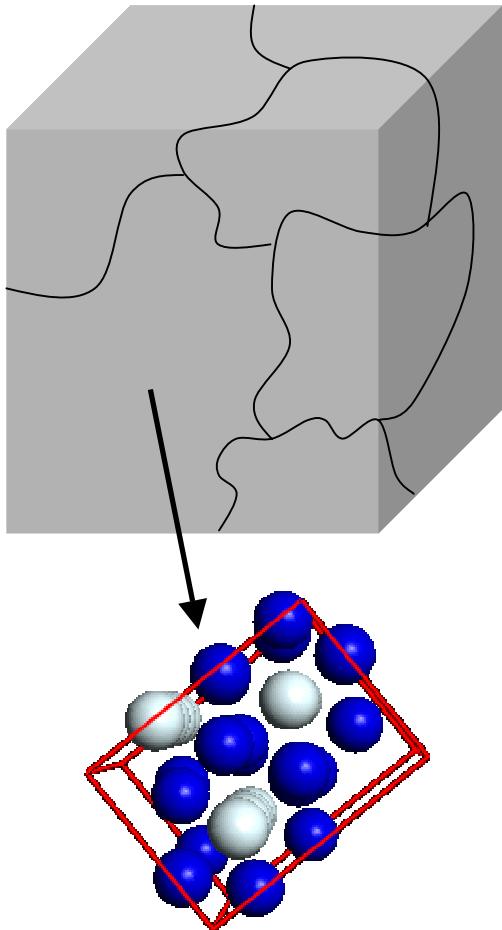
3. Annealing:



4. Annealing:



# 4D Vision



3D characterisation on a 100 nm – 1cm scale:  
position, morphology  
orientation  
plastic and elastic strain  
phase, crystallography  
chemical information

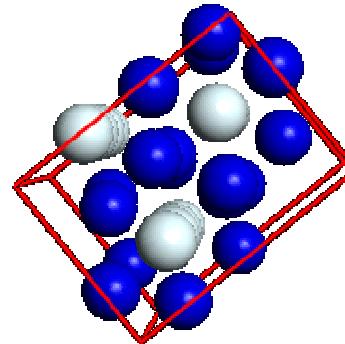
- Statistics over 100-1000 grains
- In-situ studies

# Parallel data acquisition

Position: 3D

Orientation: 3D

Lattice parameters: 6D



12D Space:

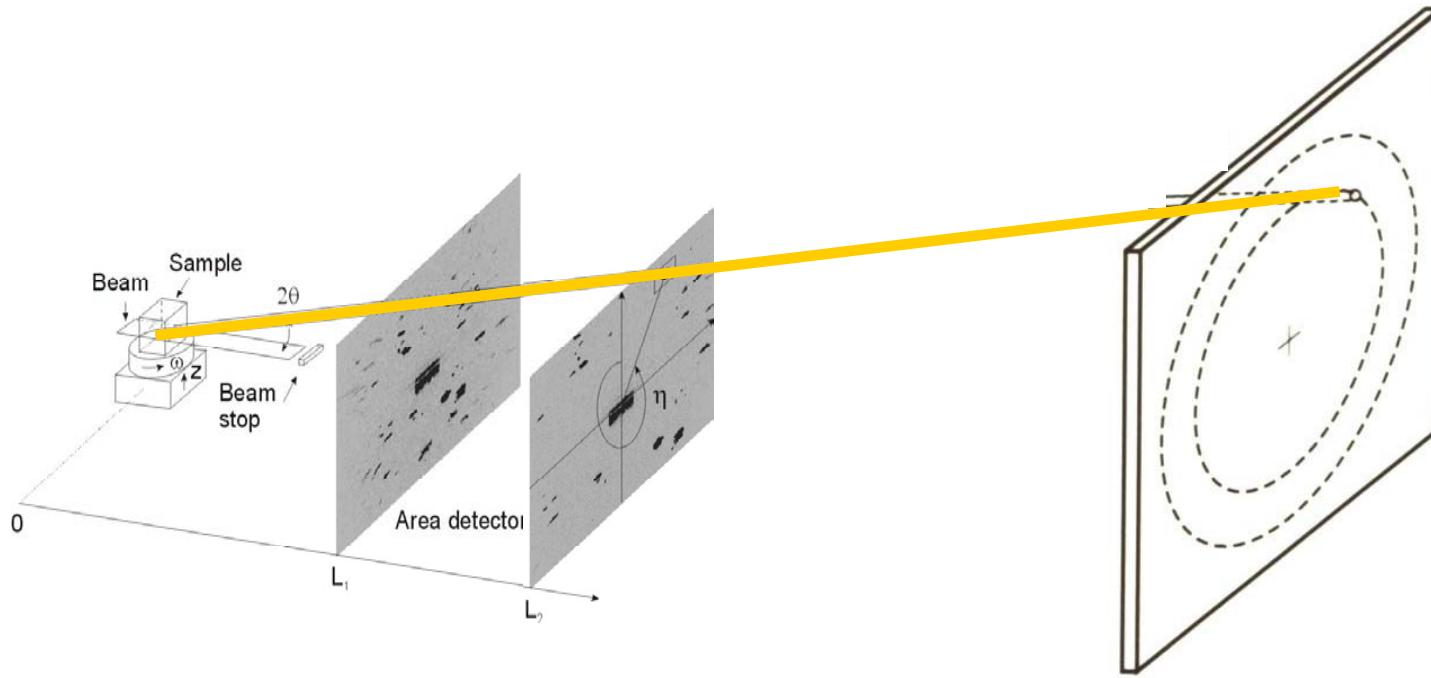
1000 x 1000 x 1000 positions:  $10^9$

0.5 deg orientation resolution  $10^4$

$10^{-4}$  strain resolution  $10^6$

$10^{19}$

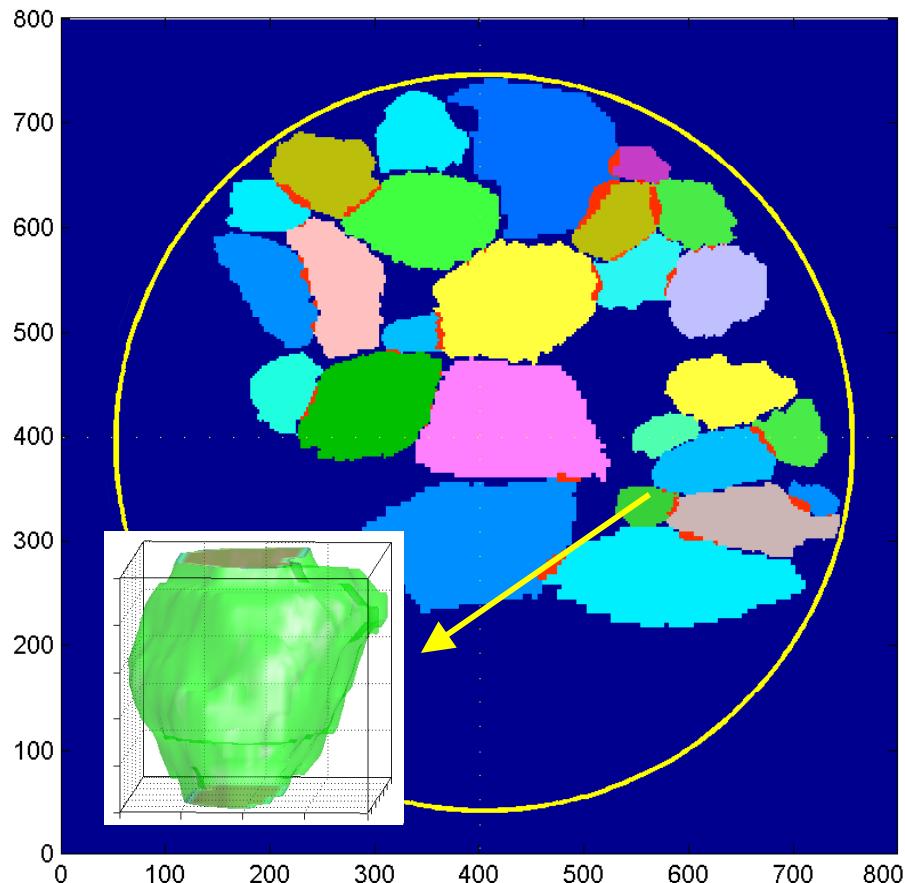
# 3DXRD Geometry @ ID11



Spatial +  
Orientation

Strain +  
Orientation +  
Crystallography

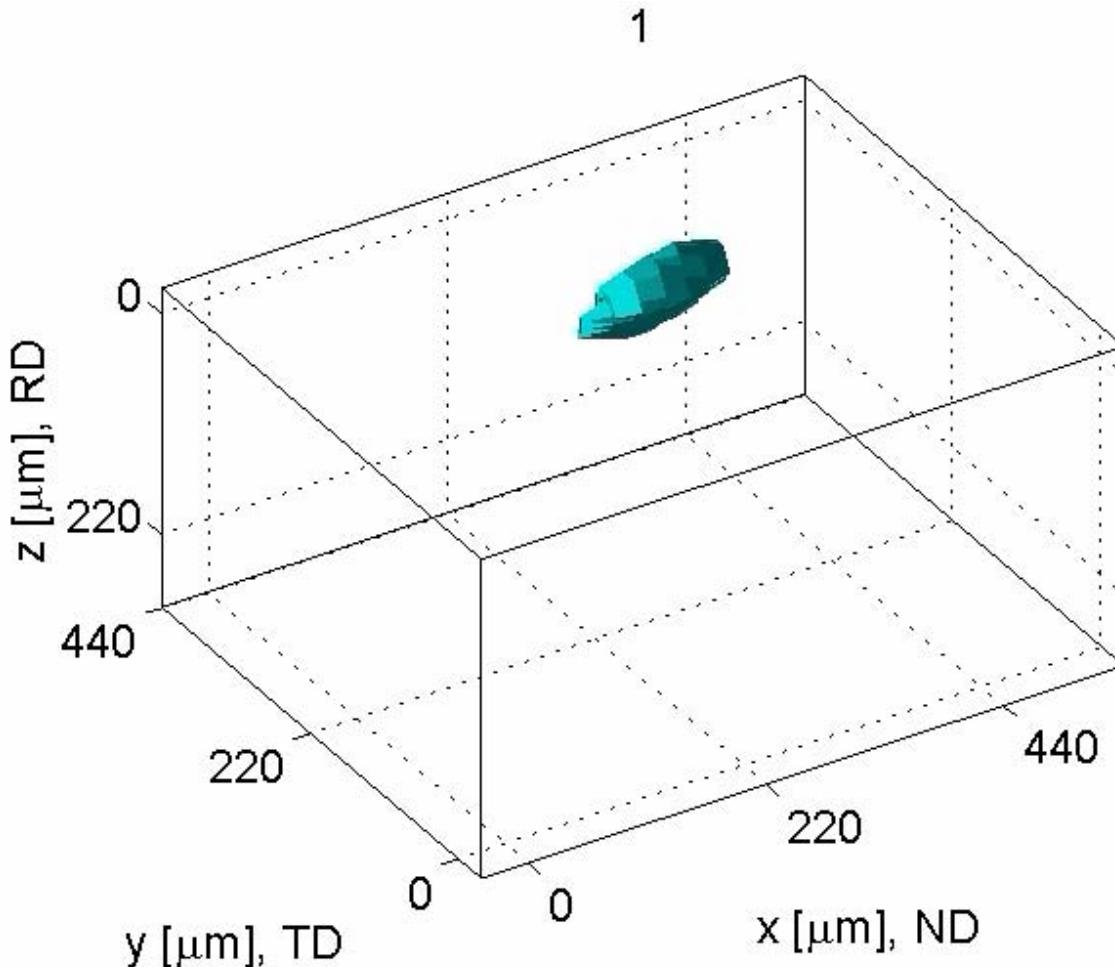
# Reconstruction of grain map



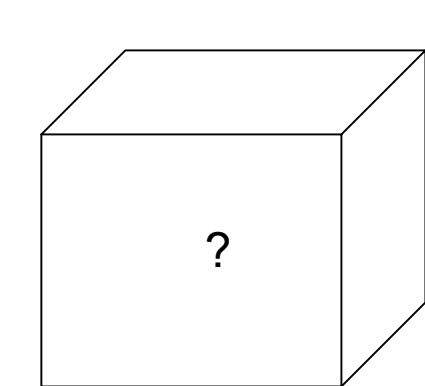
5 min acquisition time  
Resolution 5  $\mu\text{m}$

# Growth of an internal grain

Recrystallization of 42% deformed pure Al during annealing at  $\sim 200$  C.



# 3DXRD resolution



Spatial

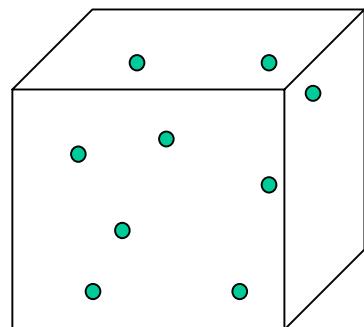
Time for 100

50 nm

1 sec

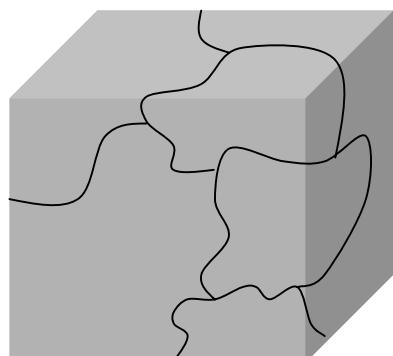
2005: 20 nm

msec



1 – 10  $\mu\text{m}$

30 sec



5  $\mu\text{m}$

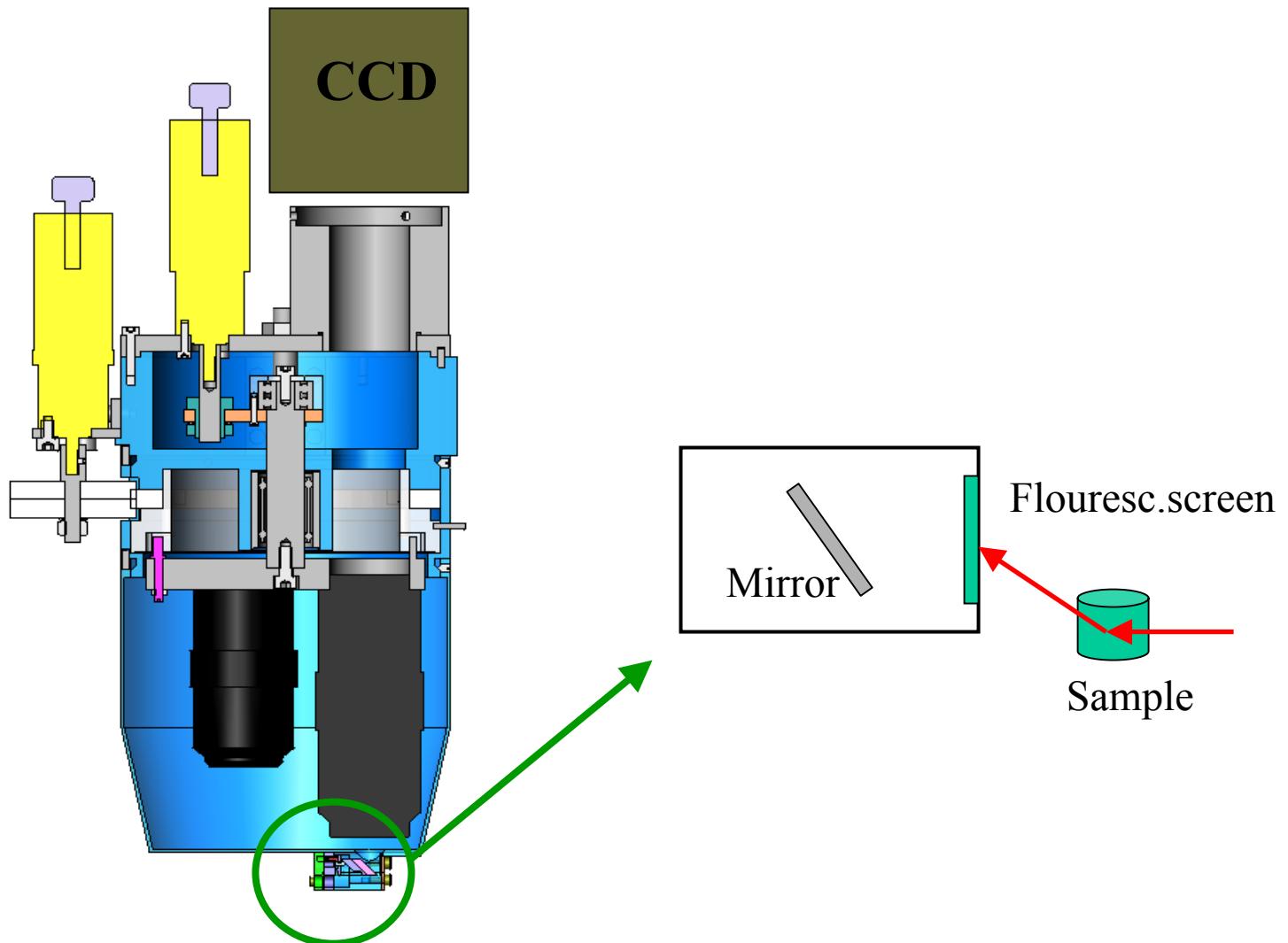
1-10 hours

limit: 2  $\mu\text{m}$

Set-ups at ID11, ESRF & SRI-CAT, APS

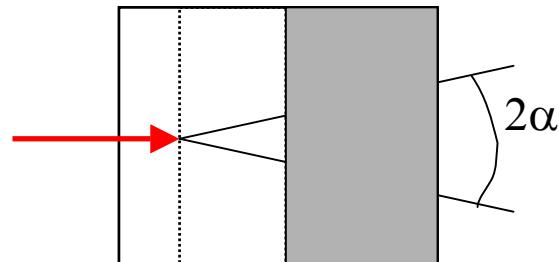
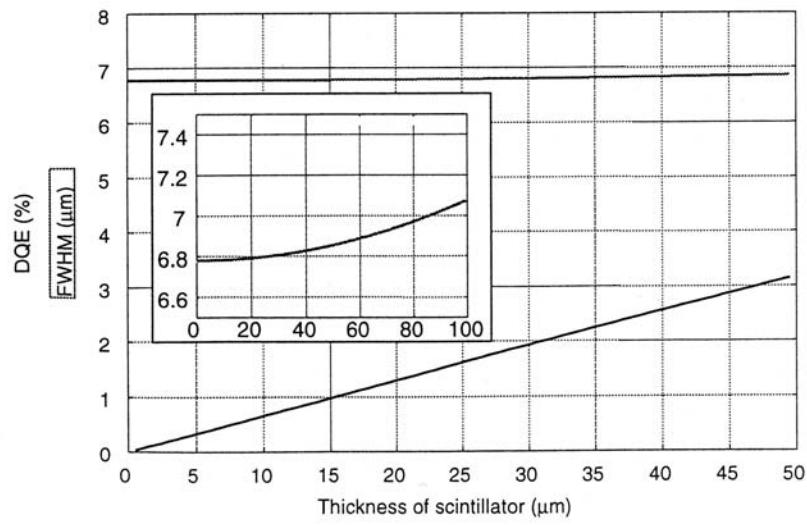
# Lens coupled CCDs

ESRF: A. Koch, P. Spanne, C. Raven, T. Martin, M. Di Michiel, P. Cloetens ..  
HASYLAB: F. Beckmann



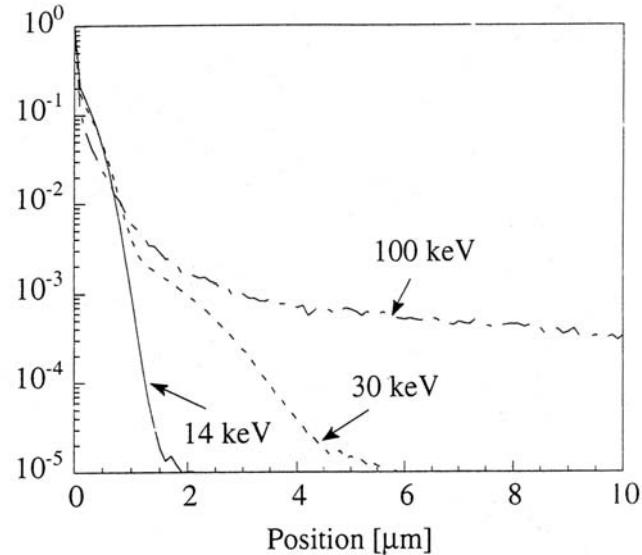
# Limitations of lens coupled CCDs

- Optical limit of 700 nm
- Thin screens with support:
  - Low efficiency (~1%)
  - Point Spread Function with large tails

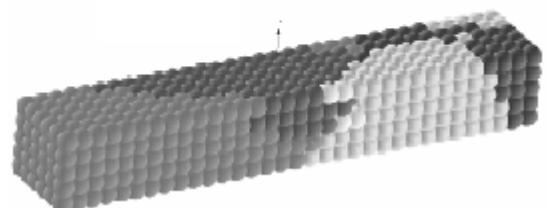
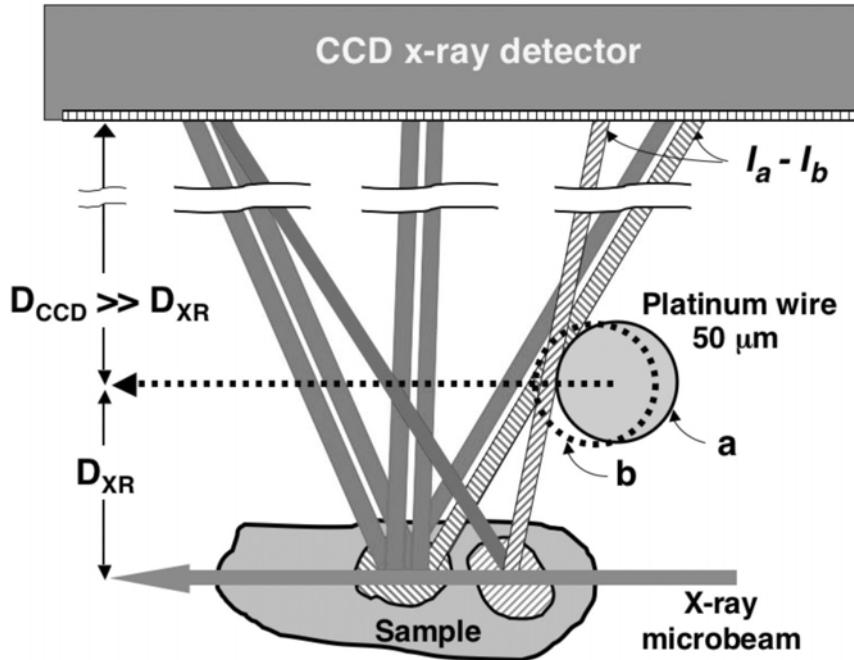


Flour. Substrate  
foil

- Point Spread Function with large tails



# Differential Aperture X-ray Microscopy



Spatial resolution:  $0.5\text{ }\mu\text{m}$

B.C. Larson *et al.* *Nature* **415**, 890 (2002)

# Materials science @ synchrotrons

## 5 years from now

4D movies with time resolution of < 1 minute

1 mm<sup>3</sup> specimens with a resolution of 1 μm<sup>3</sup>

100 μm<sup>3</sup> specimens with a resolution of 100 nm<sup>3</sup>

Combination:

tomography

diffraction (3DXRD)

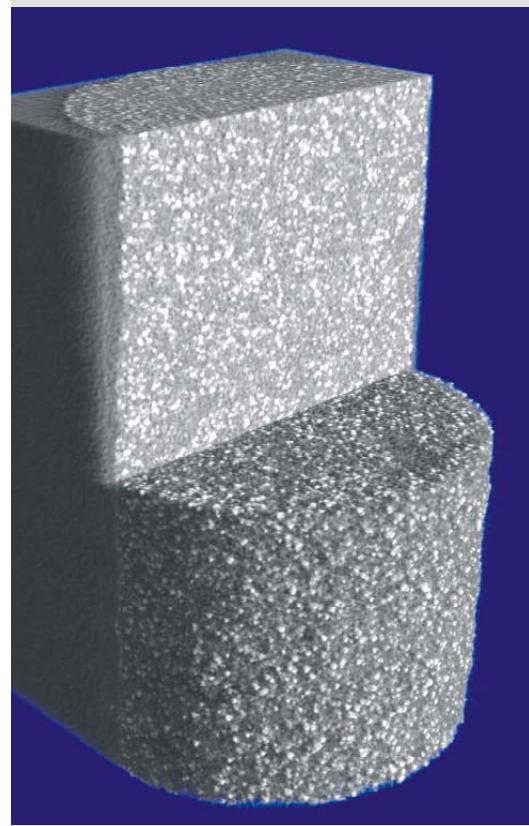
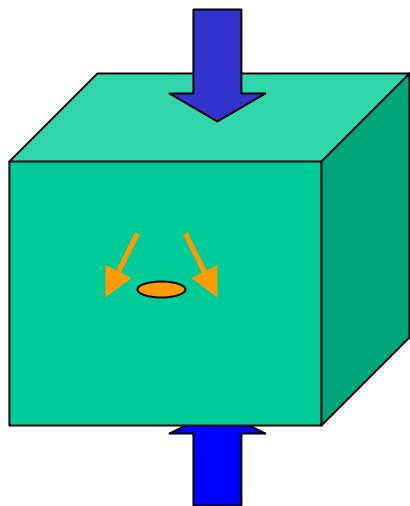
crystallography



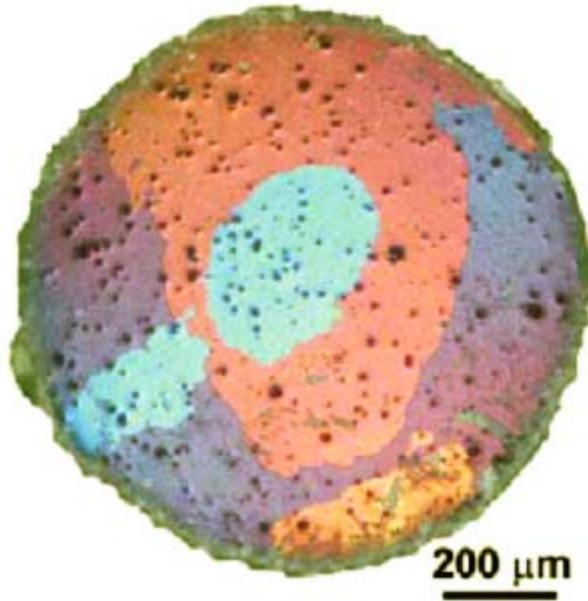
1. 3D detector banks
2. New generation of high resolution detectors

# Plastic flow

Plastic strain field



# Plastic flow in real material



*Tomography:* Local plastic flow

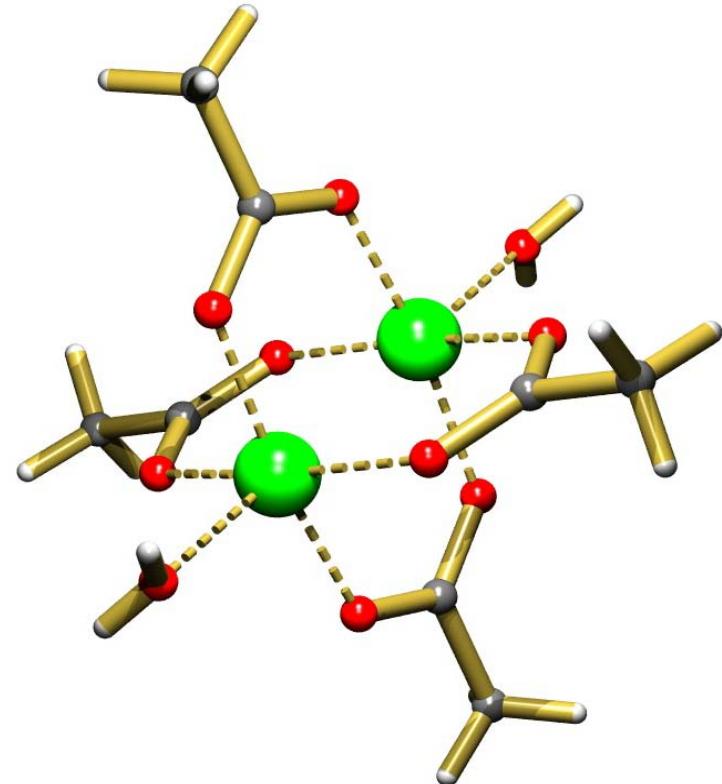
*3DXRD:* Grains, Rotations of grains

Maps of *the* local slip activity in a 3D, bulk sample

# Third route in crystallography: Structural solution of polycrystals

Validation:  $\text{Cu}(\text{C}_2\text{O}_2\text{H}_3)_2 \cdot \text{H}_2\text{O}$ .

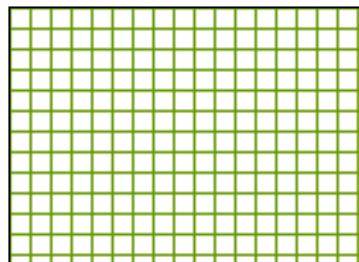
70 grains of size < 1 micron  
Cell  $\sim 1400 \text{ \AA}^3$  (C2/c)



G. Vaughan, S. Schmidt, H.F. Poulsen. *Z. Kristall.* (2004) **219**, 813-825

Brainstorm, 1<sup>st</sup> question:

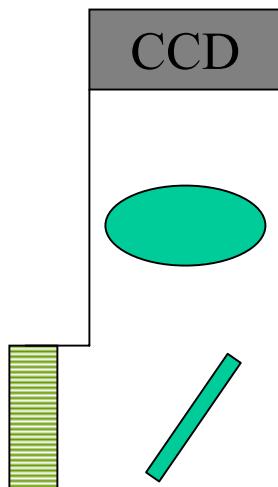
## Pixelation to 100 nm



3D screen produced by FIB?

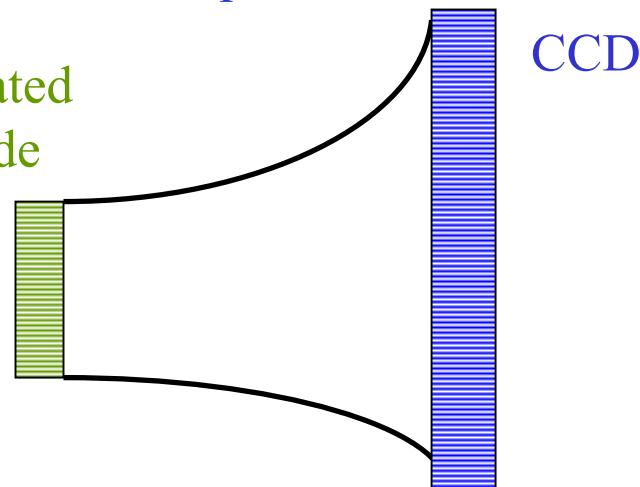
Parallax no problem

UV coupling



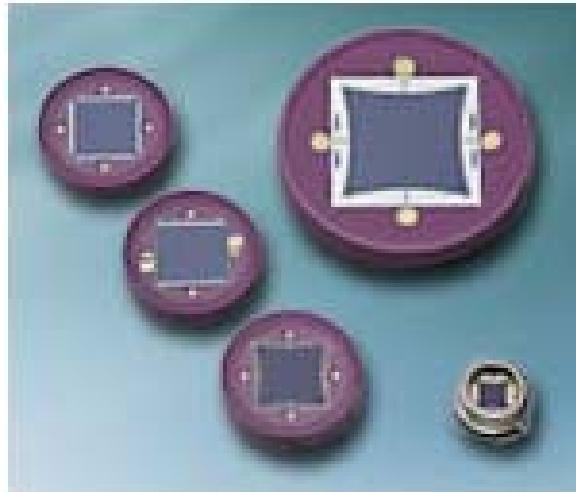
Electron optics

Pixelated  
cathode



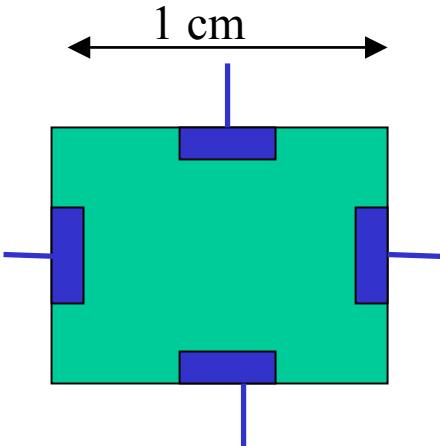
Brainstorm, 2nd idea:

## Array of Position sensitive diodes

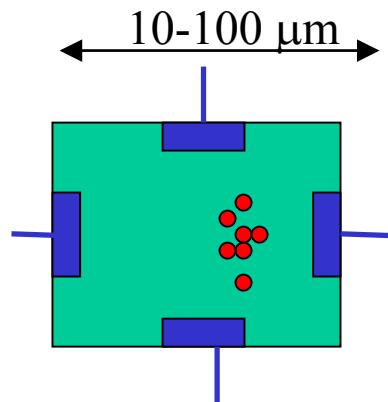


e.g. Hamamatsu

Downscale concept:



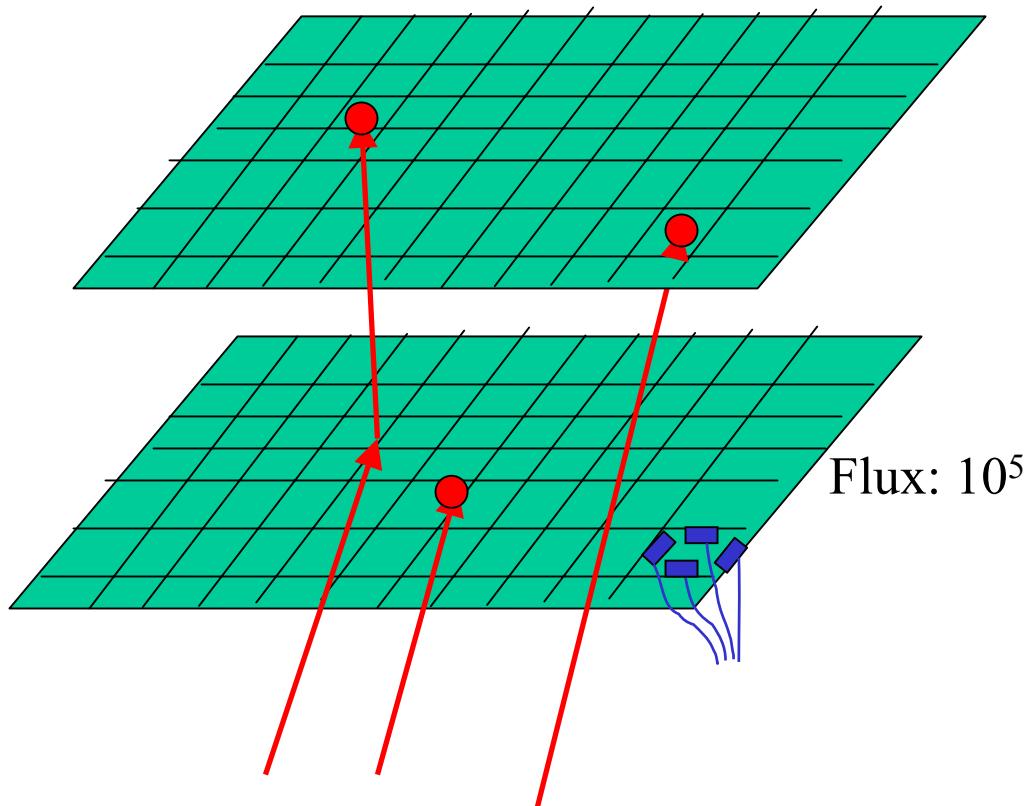
Precision: 1 in 1000



X-ray energy: 30-100 keV

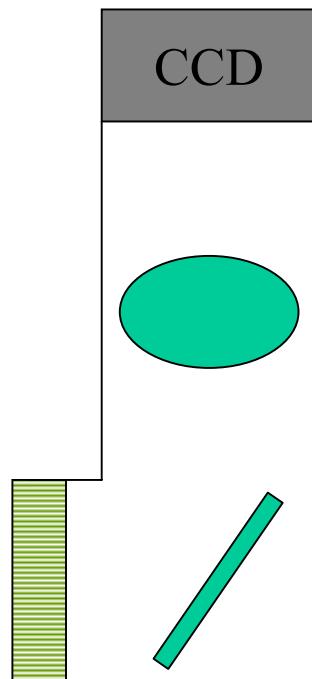
# Array of Position sensitive diodes

100 layers



Brainstorm, 3rd question:

## Energy dispersive 3DXRD



Still 2  $\mu\text{m}$  resolution

but much faster

## Case: new generation of high resolution detectors

A factor of 100 to be gained in flux

A factor of 20 in spatial resolution

Applications:

3DXRD on metals, ceramics, microelectronics, rocks, ice, bones, sugar, ...

Imaging in general, in particular at 2<sup>nd</sup> generation sources

More speculative:

Total Crystallography on drugs, ...

Free electron lasers

## Collaborators on instrumentation/software

Risø: X. Fu, E. Knudsen, E.M. Lauridsen, L. Margulies, R. Martins,  
S.F. Nielsen, S. Schmidt, H.O. Sørensen

ESRF: A. Goetz, Å. Kvick, G. Vaughan, T. Buslaps, V. Honkimäki,  
T. Martin

APS: U. Lienert, J. Almer

IMSA-Lyon: W. Ludwig

State University of N.Y.: G. Herman